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Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems

Embedded - System On Chip (SoC) refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

What are Embedded - System On Chip (SoC)?

System On Chip (SoC) integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

Details

Product Status	Active
Architecture	MCU, FPGA
Core Processor	Dual ARM® Cortex®-A53 MPCore™ with CoreSight™, Dual ARM® Cortex™ -R5 with CoreSight™
Flash Size	-
RAM Size	256KB
Peripherals	DMA, WDT
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, MMC/SD/SDIO, SPI, UART/USART, USB OTG
Speed	500MHz, 1.2GHz
Primary Attributes	Zynq®UltraScale+™ FPGA, 103K+ Logic Cells
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	784-BFBGA, FCBGA
Supplier Device Package	784-FCBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xczu2cg-1sfvc784e

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
$V_{CCO}^{(8)}$	Supply voltage for HD I/O banks.	1.140	–	3.400	V
	Supply voltage for HP I/O banks.	0.950	–	1.900	V
$V_{CCAUX_IO}^{(9)}$	Auxiliary I/O supply voltage.	1.746	1.800	1.854	V
$V_{IN}^{(10)}$	I/O input voltage.	-0.200	–	$V_{CCO} + 0.200$	V
$I_{IN}^{(11)}$	Maximum current through any PL or PS pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
GTH or GTY Transceiver					
$V_{MGTAVCC}^{(12)}$	Analog supply voltage for the GTH or GTY transceiver.	0.873	0.900	0.927	V
$V_{MGTAVTT}^{(12)}$	Analog supply voltage for the GTH or GTY transmitter and receiver termination circuits.	1.164	1.200	1.236	V
$V_{MGTVCCAUX}^{(12)}$	Auxiliary analog QPLL voltage supply for the transceivers.	1.746	1.800	1.854	V
$V_{MGTAVTRCAL}^{(12)}$	Analog supply voltage for the resistor calibration circuit of the GTH or GTY transceiver column.	1.164	1.200	1.236	V
VCU					
V_{CCINT_VCU}	Internal supply voltage for the VCU.	0.825	0.850	0.876	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: Internal supply voltage for the VCU.	0.825	0.850	0.876	V
	For -3E devices: Internal supply voltage for the VCU.	0.873	0.900	0.927	V

Table 4: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
Differential termination	Programmable differential termination (TERM_100) for HP I/O banks.	-35%	100	+35%	Ω
n	Temperature diode ideality factor.	-	1.026	-	-
r	Temperature diode series resistance.	-	2	-	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. For HP I/O banks with a V_{CCO} of 1.8V and separated V_{CCO} and V_{CCAUX_IO} power supplies, the I_L maximum current is 70 μ A.
3. This measurement represents the die capacitance at the pad, not including the package.
4. Maximum value specified for worst case process at 25°C.
5. I_{CC_PSBATT} is measured when the battery-backed RAM (BBRAM) is enabled.
6. Do not program eFUSE during device configuration (e.g., during configuration, during configuration readback, or when readback CRC is active).
7. If VRP resides at a different bank (DCI cascade), the range increases to $\pm 15\%$.
8. VRP resistor tolerance is $(240\Omega \pm 1\%)$
9. On-die input termination resistance, for more information see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 5: PS MIO Pull-up and Pull-down Current

Symbol	Description	Min	Max	Units
I_{RPU}	Pad pull-up (when selected) at $V_{IN} = 0V$, $V_{CCO_PSMIO} = 3.3V$.	20	80	μ A
	Pad pull-up (when selected) at $V_{IN} = 0V$, $V_{CCO_PSMIO} = 2.5V$.	20	80	μ A
	Pad pull-up (when selected) at $V_{IN} = 0V$, $V_{CCO_PSMIO} = 1.8V$.	15	65	μ A
I_{RPD}	Pad pull-down (when selected) at $V_{IN} = 3.3V$.	20	80	μ A
	Pad pull-down (when selected) at $V_{IN} = 2.5V$.	20	80	μ A
	Pad pull-down (when selected) at $V_{IN} = 1.8V$.	15	65	μ A

V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot

Table 6: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HD I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V _{CCO} + 0.30	100%	-0.30	100%
V _{CCO} + 0.35	100%	-0.35	90%
V _{CCO} + 0.40	100%	-0.40	78%
V _{CCO} + 0.45	100%	-0.45	40%
V _{CCO} + 0.50	100%	-0.50	24%
V _{CCO} + 0.55	100%	-0.55	18.0%
V _{CCO} + 0.60	100%	-0.60	13.0%
V _{CCO} + 0.65	100%	-0.65	10.8%
V _{CCO} + 0.70	92%	-0.70	9.0%
V _{CCO} + 0.75	92%	-0.75	7.0%
V _{CCO} + 0.80	92%	-0.80	6.0%
V _{CCO} + 0.85	92%	-0.85	5.0%
V _{CCO} + 0.90	92%	-0.90	4.0%
V _{CCO} + 0.95	92%	-0.95	2.5%

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 7: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI at -40°C to 100°C	AC Voltage Undershoot	% of UI at -40°C to 100°C
V _{CCO} + 0.30	100%	-0.30	100%
V _{CCO} + 0.35	100%	-0.35	100%
V _{CCO} + 0.40	92%	-0.40	92%
V _{CCO} + 0.45	50%	-0.45	50%
V _{CCO} + 0.50	20%	-0.50	20%
V _{CCO} + 0.55	10%	-0.55	10%
V _{CCO} + 0.60	6%	-0.60	6%
V _{CCO} + 0.65	2%	-0.65	2%
V _{CCO} + 0.70	2%	-0.70	2%

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μ s.

Table 11: Power Supply Ramp Time (Cont'd)

Symbol	Description	Min	Max	Units
T _{VCCO_PSDDR}	Ramp time from GND to 95% of V _{CCO_PSDDR} .	0.2	40	ms
T _{VCC_PSDDR_PLL}	Ramp time from GND to 95% of V _{CC_PSDDR_PLL} .	0.2	40	ms
T _{VCCO_PSIO}	Ramp time from GND to 95% of V _{CCO_PSIO} .	0.2	40	ms

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

PS I/O Levels

Table 12: PS MIO and CONFIG DC Input and Output Levels⁽¹⁾

I/O Standard	V _{IL}		V _{IH}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVCMOS33	-0.300	0.800	2.000	V _{CCO_PSIO}	0.40	2.40	12	-12
LVCMOS25	-0.300	0.700	1.700	V _{CCO_PSIO} + 0.30	0.70	1.70	12	-12
LVCMOS18	-0.300	35% V _{CCO_PSIO}	65% V _{CCO_PSIO}	V _{CCO_PSIO} + 0.30	0.45	V _{CCO_PSIO} - 0.45	12	-12

Notes:

- Tested according to relevant specifications.

Table 13: PS DDR DC Input and Output Levels⁽¹⁾

DDR Standard	V _{IL}		V _{IH}		V _{OL} ⁽²⁾		V _{OH} ⁽²⁾		I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA		
DDR4	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.8 x V _{CCO_PSDDR} - 0.150	0.8 x V _{CCO_PSDDR} + 0.150	10	-0.1		
LPDDR4	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.3 x V _{CCO_PSDDR} - 0.150	0.3 x V _{CCO_PSDDR} + 0.150	0.1	-10		
DDR3	-0.300	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.175	0.5 x V _{CCO_PSDDR} + 0.175	8	-8		
LPDDR3	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.150	0.5 x V _{CCO_PSDDR} + 0.150	8	-8		
DDR3L	-0.300	V _{REF} - 0.090	V _{REF} + 0.090	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.150	0.5 x V _{CCO_PSDDR} + 0.150	8	-8		

Notes:

- Tested according to relevant specifications.
- DDR4 V_{OL}/V_{OH} specifications are only applicable for DQ/DQS pins.

Table 31: PS NAND NV-DDR Synchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
NV-DDR ⁽¹⁾	5	200	200	200	Mb/s
	4	166.6	166.6	166.6	Mb/s
	3	133.3	133.3	133.3	Mb/s
	2	100	100	100	Mb/s
	1	66.6	66.6	66.6	Mb/s
	0	40	40	40	Mb/s

Notes:

1. The PS NAND memory controller interface for NV-DDR switching characteristics meets the requirements of the ONFI 3.1 specification.

Table 32: PS NAND SDR Asynchronous Performance

Memory Standard	Mode	Speed Grade			Units
		-3	-2	-1	
		Max	Max	Max	
SDR ⁽¹⁾⁽²⁾	5	50	50	50	Mb/s
	4	40	40	40	Mb/s
	3	33.3	33.3	33.3	Mb/s
	2	28.5	28.5	28.5	Mb/s
	1	20	20	20	Mb/s
	0	10	10	10	Mb/s

Notes:

1. The PS NAND memory controller interface for SDR switching characteristics meets the requirements of the ONFI 3.1 specification.
2. The NAND controller reference clock frequency maximum is 83 MHz.

Table 33: PS-PL Interface Performance

Symbol	Description	Min	Max	Units
FEMIOGEMCLK	EMIO gigabit Ethernet controller maximum frequency.	–	125	MHz
FEMIOSDCLK	EMIO SD controller maximum frequency.	–	25	MHz
FEMIOSPICLK	EMIO SPI controller maximum frequency.	–	25	MHz
FEMIOTRACECLK	EMIO trace controller maximum frequency.	–	125	MHz
FFCIDMACLK	Flow control interface DMA maximum frequency.	–	333	MHz
FAXICLK	Maximum AXI interface performance.	–	333	MHz
FDPLIVEVIDEO	DisplayPort controller live video interface maximum frequency.	–	300	MHz

Table 37: PS Reset Assertion Timing Requirements

Symbol	Description	Min	Typ	Max	Units
T _{PSPOR}	Required PS_POR_B assertion time. ⁽¹⁾	10	—	—	μs
T _{PSRST}	Required PS_SRST_B assertion time.	3	—	—	PS_REF_CLK Clock Cycles

Notes:

1. PS_POR_B must be asserted Low at power-up and continue to be asserted for a duration of T_{PSPOR} after all the PS supply voltages reach minimum levels. PS_POR_B must be asserted Low for the duration of T_{POR} when the PS and PL power-up at the same time and the application uses both the PS and PL after power-up.

Table 38: PS Clocks Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F _{TOPSW_MAINMAX}	TOPSW_MAIN maximum frequency.	600	533	533	MHz
F _{TOPSW_LSBUSMAX}	TOPSW_LSBUS maximum frequency.	100	100	100	MHz
F _{GDMAMAX}	FPD-DMA maximum frequency.	600	600	600	MHz
F _{DPDMAMAX}	DisplayPort DMA maximum frequency.	600	600	600	MHz
F _{LPD_SWITCH_CTRLMAX}	LPD_SWITCH_CTRL maximum frequency.	600	500	500	MHz
F _{LPD_LSBUS_CTRLMAX}	LPD_LSBUS_CTRL maximum frequency.	100	100	100	MHz
F _{ADMAMAX}	LPD-DMA maximum frequency.	600	500	500	MHz
F _{APLL_TO_LPDMAX}	APLL_TO_LPD maximum frequency.	533	533	533	MHz
F _{DPLL_TO_LPDMAX}	DPLL_TO_LPD maximum frequency.	533	533	533	MHz
F _{VPLL_TO_LPDMAX}	VPLL_TO_LPD maximum frequency.	533	533	533	MHz
F _{IOPLLU_TO_LPDMAX}	IOPLLU_TO_LPD maximum frequency.	533	533	533	MHz
F _{RPLL_TO_FPDMAX}	RPLL_TO_FPD maximum frequency.	533	533	533	MHz

PS SPI Controller Interface

Table 48: SPI Interfaces⁽¹⁾

Symbol	Description	Min	Max	Units
SPI Master Interface				
T _{DCMSPICLK}	SPI master mode clock duty cycle.	45	55	%
T _{MSPISSCLK}	Slave select asserted to first active clock edge.	1 ⁽²⁾	–	F _{SPI_REF_CLK} cycles
T _{MSPISCLKSS}	Last active clock edge to slave select deasserted.	1 ⁽²⁾	–	F _{SPI_REF_CLK} cycles
T _{MSPIDCK}	Input setup time for MISO.	–2.0	–	ns
T _{MSPICKD}	Input hold time for MISO.	0.3	–	F _{MSPICLK} cycles
T _{MSPICKO}	MOSI and slave select clock to out delay.	–2.0	5.0	ns
F _{MSPICLK}	SPI master device clock frequency.	–	50	MHz
F _{SPI_REF_CLK}	SPI reference clock frequency.	–	200	MHz
SPI Slave Interface				
T _{SPPISSCLK}	Slave select asserted to first active clock edge.	2	–	F _{SPI_REF_CLK} cycles
T _{SPPISCLKSS}	Last active clock edge to slave select deasserted.	2	–	F _{SPI_REF_CLK} cycles
T _{SPPIDCK}	Input setup time for MOSI.	5.0	–	ns
T _{SPPICKD}	Input hold time for MOSI.	1	–	F _{SPI_REF_CLK} cycles
T _{SPPICKO}	MISO clock to out delay.	0.0	13.0	ns
F _{SPPICLK}	SPI slave mode device clock frequency.	–	25	MHz
F _{SPI_REF_CLK}	SPI reference clock frequency.	–	200	MHz

Notes:

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 30 pF load.
2. Valid when two SPI_REF_CLK delays are programmed between CS and CLK for T_{MSPISSCLK}, and between CLK and CS for T_{MSPISCLKSS} in the SPI delay_reg0 register.

PS CAN Controller Interface

Table 49: CAN Interface⁽¹⁾

Symbol	Description	Min	Max	Units
T _{PWCANRX}	Receive pulse width.	1.0	–	μs
T _{PWCANTX}	Transmit pulse width.	1.0	–	μs
F _{CAN_REF_CLK}	Internally sourced CAN reference clock frequency.	–	100	MHz
	Externally sourced CAN reference clock frequency.	–	40	MHz

Notes:

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

Table 60: PS-GTR Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequencies supported.	PCI Express	100 MHz			
		SATA	125 MHz or 150 MHz			
		USB 3.0	26 MHz, 52 MHz, or 100 MHz			
		DisplayPort	27 MHz, 108 MHz, or 135 MHz			
		SGMII	125 MHz			
T_{RCLK}	Reference clock rise time.	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time.	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle.	Transceiver PLL only.	40	–	60	%
		USB 3.0 with reference clock <40 MHz.	47.5	–	52.5	%

Table 72: MIPI D-PHY Performance

Description	I/O Bank Type	Speed Grade and V _{CCINT} Operating Voltages					Units	
		0.90V		0.85V		0.72V		
		-3 ⁽¹⁾	-2 ⁽¹⁾	-1	-2	-1		
MIPI D-PHY transmitter or receiver.	HP	1500	1500	1260	1260	1260	Mb/s	

Notes:

1. In the SBVA484 package, the data rate is 1260 Mb/s.

Table 73: LVDS Native-Mode 1000BASE-X Support⁽¹⁾

Description	I/O Bank Type	Speed Grade and V _{CCINT} Operating Voltages					
		0.90V		0.85V		0.72V	
		-3	-2	-1	-2	-1	
1000BASE-X	HP	Yes					

Notes:

1. 1000BASE-X support is based on the *IEEE Standard for CSMA/CD Access Method and Physical Layer Specifications* (IEEE Std 802.3-2008).

Table 74 provides the maximum data rates for applicable memory standards using the Zynq UltraScale+ MPSoC memory PHY. Refer to [Memory Interfaces](#) for the complete list of memory interface standards supported and detailed specifications. The final performance of the memory interface is determined through a complete design implemented in the Vivado Design Suite, following guidelines in the *UltraScale Architecture PCB Design Guide* ([UG583](#)), electrical analysis, and characterization of the system.

Table 74: Maximum Physical Interface (PHY) Rate for Memory Interfaces

Memory Standard	Package ⁽¹⁾	DRAM Type	Speed Grade and V _{CCINT} Operating Voltages					Units	
			0.90V		0.85V		0.72V		
			-3	-2	-1	-2	-1		
DDR4	All FFV packages and FBVB900	Single rank component	2666	2666	2400	2400	2133	Mb/s	
		1 rank DIMM ⁽²⁾⁽³⁾⁽⁴⁾	2400	2400	2133	2133	1866	Mb/s	
		2 rank DIMM ⁽²⁾⁽⁵⁾	2133	2133	1866	1866	1600	Mb/s	
		4 rank DIMM ⁽²⁾⁽⁶⁾	1600	1600	1333	1333	N/A	Mb/s	
	SFVC784	Single rank component	2400	2400	2133	2133	1866	Mb/s	
		1 rank DIMM ⁽²⁾⁽³⁾	2133	2133	1866	1866	1600	Mb/s	
		2 rank DIMM ⁽²⁾⁽⁵⁾	1866	1866	1600	1600	1600	Mb/s	
DDR3	All FFV packages and FBVB900	Single rank component	2133	2133	2133	2133	1866	Mb/s	
		1 rank DIMM ⁽²⁾⁽³⁾	1866	1866	1866	1866	1600	Mb/s	
		2 rank DIMM ⁽²⁾⁽⁵⁾	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM ⁽²⁾⁽⁶⁾	1066	1066	1066	1066	800	Mb/s	
	SFVC784	Single rank component	1866	1866	1866	1866	1600	Mb/s	
		1 rank DIMM ⁽²⁾⁽³⁾	1600	1600	1600	1600	1600	Mb/s	
		2 rank DIMM ⁽²⁾⁽⁵⁾	1600	1600	1600	1600	1333	Mb/s	
		4 rank DIMM ⁽²⁾⁽⁶⁾	1066	1066	1066	1066	800	Mb/s	

Table 75: IOB High Density (HD) Switching Characteristics (Cont'd)

I/O Standards	T _{INBUF_DELAY_PAD_I}					T _{OUTBUF_DELAY_O_PAD}					T _{OUTBUF_DELAY_TD_PAD}					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
HSTL_I_F	0.856	0.856	0.900	0.856	0.900	1.611	1.611	1.762	1.611	1.762	1.313	1.313	1.417	1.313	1.417	ns
HSTL_I_S	0.856	0.856	0.900	0.856	0.900	1.798	1.798	1.913	1.798	1.913	1.630	1.630	1.780	1.630	1.780	ns
HSUL_12_F	0.780	0.780	0.867	0.780	0.867	1.573	1.573	1.703	1.573	1.703	1.222	1.222	1.335	1.222	1.335	ns
HSUL_12_S	0.780	0.780	0.867	0.780	0.867	1.711	1.711	1.864	1.711	1.864	1.536	1.536	1.665	1.536	1.665	ns
LVCMOS12_F_12	0.918	0.918	0.976	0.918	0.976	1.689	1.689	1.856	1.689	1.856	1.202	1.202	1.317	1.202	1.317	ns
LVCMOS12_F_4	0.918	0.918	0.976	0.918	0.976	1.742	1.742	1.922	1.742	1.922	1.353	1.353	1.478	1.353	1.478	ns
LVCMOS12_F_8	0.918	0.918	0.976	0.918	0.976	1.714	1.714	1.879	1.714	1.879	1.292	1.292	1.432	1.292	1.432	ns
LVCMOS12_S_12	0.918	0.918	0.976	0.918	0.976	2.073	2.073	2.247	2.073	2.247	1.581	1.581	1.717	1.581	1.717	ns
LVCMOS12_S_4	0.918	0.918	0.976	0.918	0.976	1.979	1.979	2.182	1.979	2.182	1.633	1.633	1.772	1.633	1.772	ns
LVCMOS12_S_8	0.918	0.918	0.976	0.918	0.976	2.205	2.205	2.406	2.205	2.406	1.767	1.767	1.928	1.767	1.928	ns
LVCMOS15_F_12	0.905	0.905	0.958	0.905	0.958	1.713	1.713	1.892	1.713	1.892	1.275	1.275	1.428	1.275	1.428	ns
LVCMOS15_F_16	0.905	0.905	0.958	0.905	0.958	1.722	1.722	1.881	1.722	1.881	1.260	1.260	1.407	1.260	1.407	ns
LVCMOS15_F_4	0.905	0.905	0.958	0.905	0.958	1.825	1.825	1.959	1.825	1.959	1.453	1.453	1.557	1.453	1.557	ns
LVCMOS15_F_8	0.905	0.905	0.958	0.905	0.958	1.778	1.778	1.930	1.778	1.930	1.378	1.378	1.458	1.378	1.458	ns
LVCMOS15_S_12	0.905	0.905	0.958	0.905	0.958	1.991	1.991	2.139	1.991	2.139	1.516	1.516	1.648	1.516	1.648	ns
LVCMOS15_S_16	0.905	0.905	0.958	0.905	0.958	2.172	2.172	2.389	2.172	2.389	1.707	1.707	1.888	1.707	1.888	ns
LVCMOS15_S_4	0.905	0.905	0.958	0.905	0.958	2.313	2.313	2.483	2.313	2.483	1.952	1.952	2.123	1.952	2.123	ns
LVCMOS15_S_8	0.905	0.905	0.958	0.905	0.958	2.170	2.170	2.400	2.170	2.400	1.817	1.817	1.984	1.817	1.984	ns
LVCMOS18_F_12	0.915	0.915	0.958	0.915	0.958	1.805	1.805	1.962	1.805	1.962	1.383	1.383	1.471	1.383	1.471	ns
LVCMOS18_F_16	0.915	0.915	0.958	0.915	0.958	1.785	1.785	1.917	1.785	1.917	1.338	1.338	1.446	1.338	1.446	ns
LVCMOS18_F_4	0.915	0.915	0.958	0.915	0.958	1.868	1.868	2.013	1.868	2.013	1.472	1.472	1.599	1.472	1.599	ns
LVCMOS18_F_8	0.915	0.915	0.958	0.915	0.958	1.797	1.797	1.979	1.797	1.979	1.384	1.384	1.487	1.384	1.487	ns
LVCMOS18_S_12	0.915	0.915	0.958	0.915	0.958	2.201	2.201	2.408	2.201	2.408	1.762	1.762	1.894	1.762	1.894	ns
LVCMOS18_S_16	0.915	0.915	0.958	0.915	0.958	2.173	2.173	2.362	2.173	2.362	1.702	1.702	1.834	1.702	1.834	ns
LVCMOS18_S_4	0.915	0.915	0.958	0.915	0.958	2.346	2.346	2.567	2.346	2.567	1.951	1.951	2.092	1.951	2.092	ns
LVCMOS18_S_8	0.915	0.915	0.958	0.915	0.958	2.292	2.292	2.511	2.292	2.511	1.848	1.848	2.008	1.848	2.008	ns
LVCMOS25_F_12	0.988	0.988	1.042	0.988	1.042	2.153	2.153	2.453	2.153	2.453	1.692	1.692	1.856	1.692	1.856	ns
LVCMOS25_F_16	0.988	0.988	1.042	0.988	1.042	2.105	2.105	2.406	2.105	2.406	1.623	1.623	1.786	1.623	1.786	ns
LVCMOS25_F_4	0.988	0.988	1.042	0.988	1.042	2.344	2.344	2.554	2.344	2.554	1.842	1.842	2.039	1.842	2.039	ns
LVCMOS25_F_8	0.988	0.988	1.042	0.988	1.042	2.184	2.184	2.516	2.184	2.516	1.726	1.726	1.910	1.726	1.910	ns
LVCMOS25_S_12	0.988	0.988	1.042	0.988	1.042	2.558	2.558	2.840	2.558	2.840	1.971	1.971	2.194	1.971	2.194	ns
LVCMOS25_S_16	0.988	0.988	1.042	0.988	1.042	2.449	2.449	2.740	2.449	2.740	1.852	1.852	2.063	1.852	2.063	ns
LVCMOS25_S_4	0.988	0.988	1.042	0.988	1.042	2.770	2.770	3.066	2.770	3.066	2.224	2.224	2.458	2.224	2.458	ns
LVCMOS25_S_8	0.988	0.988	1.042	0.988	1.042	2.663	2.663	2.963	2.663	2.963	2.091	2.091	2.373	2.091	2.373	ns
LVCMOS33_F_12	1.154	1.154	1.213	1.154	1.213	2.415	2.415	2.651	2.415	2.651	1.754	1.754	1.915	1.754	1.915	ns
LVCMOS33_F_16	1.154	1.154	1.213	1.154	1.213	2.383	2.383	2.603	2.383	2.603	1.734	1.734	1.869	1.734	1.869	ns
LVCMOS33_F_4	1.154	1.154	1.213	1.154	1.213	2.541	2.541	2.765	2.541	2.765	1.932	1.932	2.135	1.932	2.135	ns
LVCMOS33_F_8	1.154	1.154	1.213	1.154	1.213	2.603	2.603	2.822	2.603	2.822	1.937	1.937	2.130	1.937	2.130	ns
LVCMOS33_S_12	1.154	1.154	1.213	1.154	1.213	2.705	2.705	3.047	2.705	3.047	2.049	2.049	2.318	2.049	2.318	ns
LVCMOS33_S_16	1.154	1.154	1.213	1.154	1.213	2.714	2.714	3.024	2.714	3.024	2.028	2.028	2.232	2.028	2.232	ns
LVCMOS33_S_4	1.154	1.154	1.213	1.154	1.213	2.999	2.999	3.340	2.999	3.340	2.320	2.320	2.610	2.320	2.610	ns

Table 76: IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standards	T _{INBUF_DELAY_PAD_I}					T _{OUTBUF_DELAY_O_PAD}					T _{OUTBUF_DELAY_TD_PAD}					Units
	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	0.90V		0.85V		0.72V	
	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	-3	-2	-1	-2	-1	
HSTL_I_DCI_S	0.393	0.393	0.415	0.393	0.415	0.766	0.766	0.821	0.766	0.821	0.847	0.847	0.912	0.847	0.912	ns
HSTL_I_F	0.378	0.378	0.399	0.378	0.399	0.423	0.423	0.443	0.423	0.443	0.549	0.549	0.581	0.549	0.581	ns
HSTL_I_M	0.378	0.378	0.399	0.378	0.399	0.554	0.554	0.585	0.554	0.585	0.640	0.640	0.677	0.640	0.677	ns
HSTL_I_S	0.378	0.378	0.399	0.378	0.399	0.766	0.766	0.816	0.766	0.816	0.811	0.811	0.866	0.811	0.866	ns
HSUL_12_DCI_F	0.378	0.378	0.399	0.378	0.399	0.425	0.425	0.443	0.425	0.443	0.558	0.558	0.586	0.558	0.586	ns
HSUL_12_DCI_M	0.378	0.378	0.399	0.378	0.399	0.556	0.556	0.586	0.556	0.586	0.654	0.654	0.694	0.654	0.694	ns
HSUL_12_DCI_S	0.378	0.378	0.399	0.378	0.399	0.736	0.736	0.784	0.736	0.784	0.821	0.821	0.886	0.821	0.886	ns
HSUL_12_F	0.378	0.378	0.399	0.378	0.399	0.412	0.412	0.430	0.412	0.430	0.538	0.538	0.566	0.538	0.566	ns
HSUL_12_M	0.378	0.378	0.399	0.378	0.399	0.551	0.551	0.582	0.551	0.582	0.642	0.642	0.679	0.642	0.679	ns
HSUL_12_S	0.378	0.378	0.399	0.378	0.399	0.750	0.750	0.799	0.750	0.799	0.813	0.813	0.868	0.813	0.868	ns
LVCMOS12_F_2	0.512	0.512	0.555	0.512	0.555	0.672	0.672	0.692	0.672	0.692	0.898	0.898	0.922	0.898	0.922	ns
LVCMOS12_F_4	0.512	0.512	0.555	0.512	0.555	0.504	0.504	0.521	0.504	0.521	0.664	0.664	0.693	0.664	0.693	ns
LVCMOS12_F_6	0.512	0.512	0.555	0.512	0.555	0.485	0.485	0.507	0.485	0.507	0.634	0.634	0.669	0.634	0.669	ns
LVCMOS12_F_8	0.512	0.512	0.555	0.512	0.555	0.465	0.465	0.489	0.465	0.489	0.611	0.611	0.666	0.611	0.666	ns
LVCMOS12_M_2	0.512	0.512	0.555	0.512	0.555	0.708	0.708	0.727	0.708	0.727	0.916	0.916	0.945	0.916	0.945	ns
LVCMOS12_M_4	0.512	0.512	0.555	0.512	0.555	0.550	0.550	0.573	0.550	0.573	0.664	0.664	0.690	0.664	0.690	ns
LVCMOS12_M_6	0.512	0.512	0.555	0.512	0.555	0.527	0.527	0.554	0.527	0.554	0.622	0.622	0.652	0.622	0.652	ns
LVCMOS12_M_8	0.512	0.512	0.555	0.512	0.555	0.540	0.540	0.571	0.540	0.571	0.614	0.614	0.649	0.614	0.649	ns
LVCMOS12_S_2	0.512	0.512	0.555	0.512	0.555	0.767	0.767	0.803	0.767	0.803	0.990	0.990	1.024	0.990	1.024	ns
LVCMOS12_S_4	0.512	0.512	0.555	0.512	0.555	0.666	0.666	0.704	0.666	0.704	0.803	0.803	0.848	0.803	0.848	ns
LVCMOS12_S_6	0.512	0.512	0.555	0.512	0.555	0.657	0.657	0.695	0.657	0.695	0.732	0.732	0.774	0.732	0.774	ns
LVCMOS12_S_8	0.512	0.512	0.555	0.512	0.555	0.708	0.708	0.761	0.708	0.761	0.745	0.745	0.790	0.745	0.790	ns
LVCMOS15_F_12	0.414	0.414	0.445	0.414	0.445	0.500	0.500	0.522	0.500	0.522	0.647	0.647	0.682	0.647	0.682	ns
LVCMOS15_F_2	0.414	0.414	0.445	0.414	0.445	0.702	0.702	0.722	0.702	0.722	0.919	0.919	0.940	0.919	0.940	ns
LVCMOS15_F_4	0.414	0.414	0.445	0.414	0.445	0.579	0.579	0.601	0.579	0.601	0.755	0.755	0.781	0.755	0.781	ns
LVCMOS15_F_6	0.414	0.414	0.445	0.414	0.445	0.547	0.547	0.569	0.547	0.569	0.711	0.711	0.742	0.711	0.742	ns
LVCMOS15_F_8	0.414	0.414	0.445	0.414	0.445	0.518	0.518	0.538	0.518	0.538	0.686	0.686	0.703	0.686	0.703	ns
LVCMOS15_M_12	0.414	0.414	0.445	0.414	0.445	0.607	0.607	0.644	0.607	0.644	0.637	0.637	0.676	0.637	0.676	ns
LVCMOS15_M_2	0.414	0.414	0.445	0.414	0.445	0.741	0.741	0.770	0.741	0.770	0.938	0.938	0.962	0.938	0.962	ns
LVCMOS15_M_4	0.414	0.414	0.445	0.414	0.445	0.625	0.625	0.651	0.625	0.651	0.754	0.754	0.786	0.754	0.786	ns
LVCMOS15_M_6	0.414	0.414	0.445	0.414	0.445	0.576	0.576	0.604	0.576	0.604	0.674	0.674	0.710	0.674	0.710	ns
LVCMOS15_M_8	0.414	0.414	0.445	0.414	0.445	0.568	0.568	0.601	0.568	0.601	0.639	0.639	0.681	0.639	0.681	ns
LVCMOS15_S_12	0.414	0.414	0.445	0.414	0.445	0.788	0.788	0.855	0.788	0.855	0.695	0.695	0.733	0.695	0.733	ns
LVCMOS15_S_2	0.414	0.414	0.445	0.414	0.445	0.829	0.829	0.864	0.829	0.864	1.039	1.039	1.079	1.039	1.079	ns
LVCMOS15_S_4	0.414	0.414	0.445	0.414	0.445	0.687	0.687	0.725	0.687	0.725	0.813	0.813	0.851	0.813	0.851	ns
LVCMOS15_S_6	0.414	0.414	0.445	0.414	0.445	0.671	0.671	0.710	0.671	0.710	0.726	0.726	0.763	0.726	0.763	ns
LVCMOS15_S_8	0.414	0.414	0.445	0.414	0.445	0.704	0.704	0.755	0.704	0.755	0.721	0.721	0.758	0.721	0.758	ns
LVCMOS18_F_12	0.418	0.418	0.445	0.418	0.445	0.573	0.573	0.601	0.573	0.601	0.731	0.731	0.769	0.731	0.769	ns
LVCMOS18_F_2	0.418	0.418	0.445	0.418	0.445	0.739	0.739	0.760	0.739	0.760	0.945	0.945	0.971	0.945	0.971	ns
LVCMOS18_F_4	0.418	0.418	0.445	0.418	0.445	0.609	0.609	0.630	0.609	0.630	0.778	0.778	0.802	0.778	0.802	ns
LVCMOS18_F_6	0.418	0.418	0.445	0.418	0.445	0.603	0.603	0.633	0.603	0.633	0.781	0.781	0.808	0.781	0.808	ns

Table 78: Input Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
SUB_LVDS, 1.8V	SUB_LVDS	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	–
SLVS, 1.8V	SLVS_400_18	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	–
SLVS, 2.5V	SLVS_400_25	1.25 – 0.125	1.25 + 0.125	0 ⁽⁶⁾	–
LVPECL, 2.5V	LVPECL	1.25 – 0.125	1.25 + 0.125	0 ⁽⁶⁾	–
MIPI D-PHY (high speed) 1.2V	MIPI_DPHY_DCI_HS	0.2 – 0.125	0.2 + 0.125	0 ⁽⁶⁾	–
MIPI D-PHY (low power) 1.2V	MIPI_DPHY_DCI_LP	0.715 – 0.2	0.715 + 0.2	0 ⁽⁶⁾	–

Notes:

1. The input delay measurement methodology parameters for LVDCI/HSLVDCI are the same for LVCMS standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H .
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF}/V_{MEAS} parameters found in IBIS models and/or noted in Figure 1.
6. The value given is the differential input voltage.

Table 88: Global Clock Input to Output Delay Without MMCM (Far Clock Region)

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, without MMCM.									
TICKOF_FAR	Global clock input and output flip-flop without MMCM (far clock region).	XCZU2	N/A	5.27	5.68	5.80	6.13	ns	
		XCZU3	N/A	5.27	5.68	5.80	6.13	ns	
		XCZU4	5.07	6.06	6.61	6.23	7.10	ns	
		XCZU5	5.07	6.06	6.61	6.23	7.10	ns	
		XCZU6	5.38	6.49	6.97	7.14	7.59	ns	
		XCZU7	5.39	6.54	7.01	7.16	7.62	ns	
		XCZU9	5.38	6.49	6.97	7.14	7.59	ns	
		XCZU11	6.18	7.41	8.11	7.66	8.99	ns	
		XCZU15	5.38	6.49	6.96	7.19	7.71	ns	
		XCZU17	6.21	7.53	8.07	8.36	8.90	ns	
		XCZU19	6.21	7.53	8.07	8.36	8.90	ns	

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

Table 89: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with MMCM.									
TICKOFMMCMCC	Global clock input and output flip-flop with MMCM.	XCZU2	N/A	2.22	2.43	2.96	2.94	ns	
		XCZU3	N/A	2.22	2.43	2.96	2.94	ns	
		XCZU4	2.47	2.47	2.78	3.04	3.35	ns	
		XCZU5	2.47	2.47	2.78	3.04	3.35	ns	
		XCZU6	2.15	2.15	2.36	2.86	2.86	ns	
		XCZU7	2.32	2.32	2.57	3.06	3.13	ns	
		XCZU9	2.15	2.15	2.36	2.86	2.86	ns	
		XCZU11	2.64	2.64	2.96	3.25	3.55	ns	
		XCZU15	2.18	2.18	2.38	2.88	2.90	ns	
		XCZU17	2.44	2.44	2.66	3.19	3.17	ns	
		XCZU19	2.44	2.44	2.66	3.19	3.17	ns	

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Device Pin-to-Pin Input Parameter Guidelines

The pin-to-pin numbers in [Table 90](#) and [Table 91](#) are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

Table 90: Global Clock Input Setup and Hold With 3.3V HD I/O without MMCM

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units	
			0.90V	0.85V	0.72V	-3	-2		
			-3	-2	-1	-2	-1		
Input Setup and Hold Time Relative to Global Clock Input Signal using SSTL15 Standard. (1)(2)(3)									
T_{PSFD_ZU2}	Global clock input and input flip-flop (or latch) without MMCM.	Setup	XCZU2	N/A	2.27	2.37	2.55	2.64	ns
T_{PHFD_ZU2}		Hold			-0.36	-0.36	-0.14	-0.14	ns
T_{PSFD_ZU3}		Setup	XCZU3	N/A	2.27	2.37	2.55	2.64	ns
T_{PHFD_ZU3}		Hold			-0.36	-0.36	-0.14	-0.14	ns
T_{PSFD_ZU4}		Setup	XCZU4	1.28	2.01	2.07	2.59	2.59	ns
T_{PHFD_ZU4}		Hold			-0.28	-0.28	-0.09	-0.09	ns
T_{PSFD_ZU5}		Setup	XCZU5	1.28	2.01	2.07	2.59	2.59	ns
T_{PHFD_ZU5}		Hold			-0.28	-0.28	-0.09	-0.09	ns
T_{PSFD_ZU6}		Setup	XCZU6	0.96	1.79	1.86	1.93	2.02	ns
T_{PHFD_ZU6}		Hold			-0.05	-0.05	-0.05	0.27	0.42
T_{PSFD_ZU7}		Setup	XCZU7	1.43	2.32	2.42	2.60	2.69	ns
T_{PHFD_ZU7}		Hold			-0.40	-0.40	-0.21	-0.21	ns
T_{PSFD_ZU9}		Setup	XCZU9	0.96	1.79	1.86	1.93	2.02	ns
T_{PHFD_ZU9}		Hold			-0.05	-0.05	-0.05	0.27	0.42
T_{PSFD_ZU11}		Setup	XCZU11	1.28	2.01	2.07	2.59	2.59	ns
T_{PHFD_ZU11}		Hold			-0.29	-0.29	-0.09	0.19	ns
T_{PSFD_ZU15}		Setup	XCZU15	0.96	1.79	1.85	1.92	2.01	ns
T_{PHFD_ZU15}		Hold			-0.04	-0.04	-0.04	0.27	0.43
T_{PSFD_ZU17}		Setup	XCZU17	1.41	2.29	2.38	2.57	2.65	ns
T_{PHFD_ZU17}		Hold			-0.38	-0.38	-0.19	-0.19	ns
T_{PSFD_ZU19}		Setup	XCZU19	1.41	2.29	2.38	2.57	2.65	ns
T_{PHFD_ZU19}		Hold			-0.38	-0.38	-0.19	-0.19	ns

Notes:

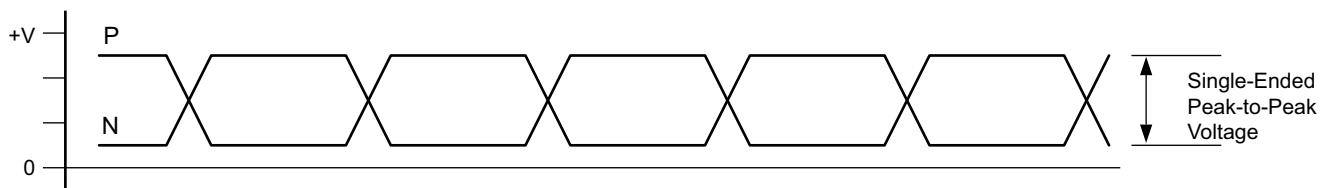
1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, slowest temperature, and slowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, fastest temperature, and fastest voltage.
2. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 105: GTH Transceiver Protocol List

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
CAUI-10	IEEE 802.3-2012	10.3125	Compliant
nPPI	IEEE 802.3-2012	10.3125	Compliant
10GBASE-KR ⁽¹⁾	IEEE 802.3-2012	10.3125	Compliant
40GBASE-KR	IEEE 802.3-2012	10.3125	Compliant
SFP+	SFF-8431 (SR and LR)	9.95328–11.10	Compliant
XFP	INF-8077i, revision 4.5	10.3125	Compliant
RXAUI	CEI-6G-SR	6.25	Compliant
XAUI	IEEE 802.3-2012	3.125	Compliant
1000BASE-X	IEEE 802.3-2012	1.25	Compliant
5.0G Ethernet	IEEE 802.3bx (PAR)	5	Compliant
2.5G Ethernet	IEEE 802.3bx (PAR)	2.5	Compliant
HiGig, HiGig+, HiGig2	IEEE 802.3-2012	3.74, 6.6	Compliant
OTU2	ITU G.8251	10.709225	Compliant
OTU4 (OTL4.10)	OIF-CEI-11G-SR	11.180997	Compliant
OC-3/12/48/192	GR-253-CORE	0.1555–9.956	Compliant
TFI-5	OIF-TFI5-0.1.0	2.488	Compliant
Interlaken	OIF-CEI-6G, OIF-CEI-11G-SR	4.25–12.5	Compliant
PCIe Gen1, 2, 3	PCI Express base 3.0	2.5, 5.0, and 8.0	Compliant
SDI ⁽²⁾	SMPTE 424M-2006	0.27–2.97	Compliant
UHD-SDI ⁽²⁾	SMPTE ST-2081 6G, SMPTE ST-2082 12G	6 and 12	Compliant
Hybrid memory cube (HMC)	HMC-15G-SR	10, 12.5, and 15.0	Compliant
MoSys Bandwidth Engine	CEI-11-SR and CEI-11-SR (overclocked)	10.3125, 15.5	Compliant
CPRI	CPRI_v_6_1_2014-07-01	0.6144–12.165	Compliant
HDMI ⁽²⁾	HDMI 2.0	All	Compliant
Passive optical network (PON)	10G-EAPON, 1G-EAPON, NG-PON2, XG-PON, and 2.5G-PON	0.155–10.3125	Compliant
JESD204a/b	OIF-CEI-6G, OIF-CEI-11G	3.125–12.5	Compliant
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort ⁽²⁾	DP 1.2B CTS	1.62–5.4	Compliant
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625–12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	up to 11.180997	Compliant

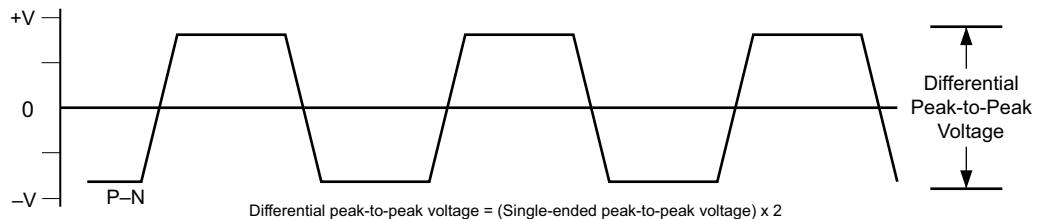
Notes:

1. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
2. This protocol requires external circuitry to achieve compliance.



X16653-101316

Figure 5: Single-Ended Peak-to-Peak Voltage



X16639-101316

Figure 6: Differential Peak-to-Peak Voltage

[Table 107](#) and [Table 108](#) summarize the DC specifications of the clock input of the GTY transceivers in Zynq UltraScale+ MPSoCs. Consult the *UltraScale Architecture GTY Transceiver User Guide (UG578)* for further details.

Table 107: GTY Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	250	—	2000	mV
R_{IN}	Differential input resistance	—	100	—	Ω
C_{EXT}	Required external AC coupling capacitor	—	10	—	nF

Table 108: GTY Transceiver Clock Output Level Specification

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{OL}	Output Low voltage for P and N	$R_T = 100\Omega$ across P and N signals	100	—	330	mV
V_{OH}	Output High voltage for P and N	$R_T = 100\Omega$ across P and N signals	500	—	700	mV
V_{DDOUT}	Differential output voltage (P-N), P = High (N-P), N = High	$R_T = 100\Omega$ across P and N signals	300	—	430	mV
V_{CMOUT}	Common mode voltage	$R_T = 100\Omega$ across P and N signals	300	—	500	mV

GTY Transceiver Electrical Compliance

The *UltraScale Architecture GTY Transceiver User Guide* ([UG578](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 117](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

Table 117: GTY Transceiver Protocol List

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
CAUI-4	IEEE 802.3-2012	25.78125	Compliant
28 Gb/s backplane	CEI-25G-LR	25–28.05	Compliant
Interlaken	OIF-CEI-6G, OIF-CEI-11GSR, OIF-CEI-28G-MR	4.25–25.78125	Compliant
100GBASE-KR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
100GBASE-CR4	IEEE 802.3bj-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
50GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
50GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
25GBASE-KR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
25GBASE-CR4	IEEE 802.3by-2014, CEI-25G-LR	25.78125	Compliant ⁽¹⁾
OTU4 (OTL4.4) CFP2	OIF-CEI-28G-VSR	27.952493–32.75	Compliant
OTU4 (OTL4.4) CFP	OIF-CEI-11G-MR	11.18–13.1	Compliant
CAUI-10	IEEE 802.3-2012	10.3125	Compliant
nPPI	IEEE 802.3-2012	10.3125	Compliant
10GBASE-KR ⁽²⁾	IEEE 802.3-2012	10.3125	Compliant
SFP+	SFF-8431 (SR and LR)	9.95328–11.10	Compliant
XFP	INF-8077i, revision 4.5	10.3125	Compliant
RXAUI	CEI-6G-SR	6.25	Compliant
XAUI	IEEE 802.3-2012	3.125	Compliant
1000BASE-X	IEEE 802.3-2012	1.25	Compliant
5.0G Ethernet	IEEE 802.3bx (PAR)	5	Compliant
2.5G Ethernet	IEEE 802.3bx (PAR)	2.5	Compliant
HiGig, HiGig+, HiGig2	IEEE 802.3-2012	3.74, 6.6	Compliant
QSGMII	QSGMII v1.2 (Cisco System, ENG-46158)	5	Compliant
OTU2	ITU G.8251	10.709225	Compliant
OTU4 (OTL4.10)	OIF-CEI-11G-SR	11.180997	Compliant
OC-3/12/48/192	GR-253-CORE	0.1555–9.956	Compliant
PCIe Gen1, 2, 3	PCI Express base 3.0	2.5, 5.0, and 8.0	Compliant
SDI ⁽³⁾	SMPTE 424M-2006	0.27–2.97	Compliant
UHD-SDI ⁽³⁾	SMPTE ST-2081 6G, SMPTE ST-2082 12G	6 and 12	Compliant
Hybrid memory cube (HMC)	HMC-15G-SR	10, 12.5, and 15.0	Compliant
MoSys bandwidth engine	CEI-11-SR and CEI-11-SR (overclocked)	10.3125, 15.5	Compliant
CPRI	CPRI_v_6_1_2014-07-01	0.6144–12.165	Compliant
Passive optical network (PON)	10G-EPON, 1G-EPON, NG-PON2, XG-PON, and 2.5G-PON	0.155–10.3125	Compliant
JESD204a/b	OIF-CEI-6G, OIF-CEI-11G	3.125–12.5	Compliant

Table 117: GTY Transceiver Protocol List (Cont'd)

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort	DP 1.2B CTS	1.62–5.4	Compliant ⁽³⁾
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625 - 12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	All rates	Compliant

Notes:

1. 25 dB loss at Nyquist without FEC.
2. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
3. This protocol requires external circuitry to achieve compliance.

Table 119: Maximum Performance for Interlaken 6 x 25.78125 Gb/s and 6 x 28.21 Gb/s Protocol and Lane Logic Mode Designs

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages								Units	
		0.90V		0.85V			0.72V				
		-3 ⁽¹⁾	-2 ⁽¹⁾	-1	-2	-1					
F _{RX_SERDES_CLK}	Receive serializer/deserializer clock	440.79	440.79	N/A	402.84	N/A				MHz	
F _{TX_SERDES_CLK}	Transmit serializer/deserializer clock	440.79	440.79	N/A	402.84	N/A				MHz	
F _{DRP_CLK}	Dynamic reconfiguration port clock	250.00	250.00	N/A	250.00	N/A				MHz	
		Min ⁽²⁾	Max	Min ⁽²⁾	Max	Min	Max	Min ⁽²⁾	Max	Min Max	
F _{CORE_CLK}	Interlaken core clock	412.50 ⁽³⁾	479.20	412.50 ⁽³⁾	479.20	N/A	412.50	429.69	N/A	MHz	
F _{LBUS_CLK}	Interlaken local bus clock	300.00 ⁽⁴⁾	349.52	300.00 ⁽⁴⁾	349.52	N/A	300.00	349.52	N/A	MHz	

Notes:

1. 6 x 28.21 mode is only supported in the -2 (V_{CCINT}=0.85V) and -3 (V_{CCINT}=0.90V) speed grades.
2. These are the minimum clock frequencies at the maximum lane performance.
3. The minimum value for CORE_CLK is 451.36 MHz for the 6 x 28.21 Gb/s protocol.
4. The minimum value for LBUS_CLK is 330.00 MHz for the 6 x 28.21 Gb/s protocol.

Table 120: Maximum Performance for Interlaken 12 x 25.78125 Gb/s Lane Logic Only Mode Designs

Symbol	Description	Speed Grade and V _{CCINT} Operating Voltages								Units	
		0.90V		0.85V			0.72V				
		-3	-2	-1	-2	-1					
F _{RX_SERDES_CLK}	Receive serializer/deserializer clock	402.84	402.84	N/A	N/A	N/A				MHz	
F _{TX_SERDES_CLK}	Transmit serializer/deserializer clock	402.84	402.84	N/A	N/A	N/A				MHz	
F _{DRP_CLK}	Dynamic reconfiguration port clock	250.00	250.00	N/A	N/A	N/A				MHz	
F _{CORE_CLK}	Interlaken core clock	412.50	412.50	N/A	N/A	N/A				MHz	
F _{LBUS_CLK}	Interlaken local bus clock	349.52	349.52	N/A	N/A	N/A				MHz	

PL SYSMON I2C/PMBus Interfaces

Table 125: PL SYSMON I2C Fast Mode Interface Switching Characteristics⁽¹⁾

Symbol	Description	Min	Max	Units
T_{SMFCKL}	SCL Low time	1.3	–	μs
T_{SMFCKH}	SCL High time	0.6	–	μs
T_{SMFCKO}	SDAO clock-to-out delay	–	900	ns
T_{SMFDCK}	SDAI setup time	100	–	ns
F_{SMFCLK}	SCL clock frequency	–	400	kHz

Notes:

1. The test conditions are configured to the LVC MOS 1.8V I/O standard.

Table 126: PL SYSMON I2C Standard Mode Interface Switching Characteristics⁽¹⁾

Symbol	Description	Min	Max	Units
T_{SMSCKL}	SCL Low time	4.7	–	μs
T_{SMSCKH}	SCL High time	4.0	–	μs
T_{SMSCKO}	SDAO clock-to-out delay	–	3450	ns
T_{SMSDCK}	SDAI setup time	250	–	ns
F_{SMSCLK}	SCL clock frequency	–	100	kHz

Notes:

1. The test conditions are configured to the LVC MOS 1.8V I/O standard.